



WANSEMI
万尚半导体

WP3030KP3

Enhancement Mode N-Channel Power MOSFET

PDFN3X3/NMOS/30V/±20V/1.5V/30A/7.3mΩ

Rev1.0

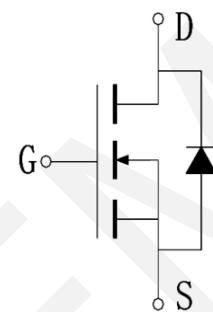


30V, 7.3mΩ, 30A, Single N-Channel

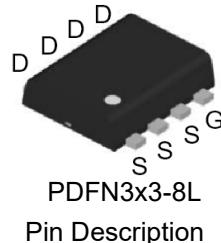
1. Features

- ◆ 30V MOSFET technology
- ◆ Low on-state resistance
- ◆ Fast switching
- ◆ $V_{GS} \pm 20V$
- ◆ 100% RG Tested
- ◆ 100% UIS Tested

| V_{DS} | $R_{DS(on)}$ Typ. | I_D Max. |
|----------|-------------------|------------|
| 30V | 7.3mΩ @ 10V | 30A |
| | 10.5mΩ @ 4.5V | |



Schematic Diagram



Pin Description

3. Package Marking and Ordering Information

| Part no. | Marking | Package | PCS/Reel | PCS/CTN. |
|-----------|-----------|---------|----------|----------|
| WP3030KP3 | WP3030KP3 | PDFN3x3 | 5,000 | 50,000 |

4. Absolute Max Ratings at $T_a=25^\circ C$ (Note1)

| Parameter | Symbol | Maximum | Units |
|---|-----------|-------------|-------|
| Drain to Source Voltage | V_{DSS} | 30 | V |
| Gate to Source Voltage | V_{GSS} | ± 20 | V |
| Drain Current (DC) | I_D | 30 | A |
| Drain Current (Pulse), $PW \leq 300\mu s$ | I_{DP} | 120 | A |
| Total Dissipation | P_D | 22 | W |
| Avalanche Energy, Single Pulsed | E_{AS} | 72.25 | mJ |
| Junction Temperature | T_j | 150 | °C |
| Storage Temperature | T_{stg} | -55 to +150 | °C |

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

**5.Thermal Resistance Ratings (Note 2)**

| Parameter | Symbol | Value | Unit |
|------------------|------------------|-------|------|
| Junction to case | R _{AJC} | 5.7 | °C/W |

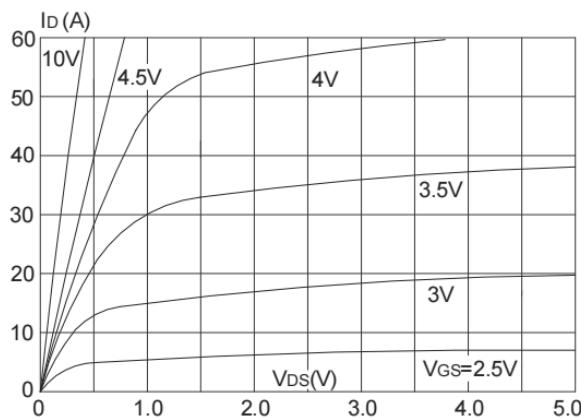
Note 2: When mounted on 1 inch square copper board $t \leq 10\text{sec}$ The value in any given application depends on the user's specific board design.

6.Electrical Characteristics at Ta=25°C (Note 3)

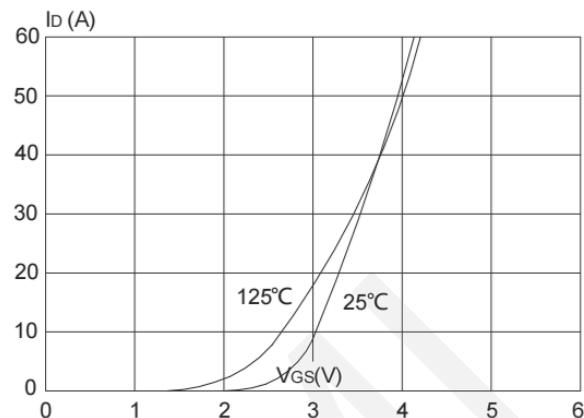
| Parameter | Symbol | Test Conditions | Min. | Typ. | Max. | Units |
|--|----------------------|---|------|------|------|-------|
| Drain to Source Breakdown Voltage | V _{(BR)DSS} | I _D = 250μA, V _{GS} = 0V | 30 | - | - | V |
| Zero-Gate Voltage Drain Current | I _{DSS} | V _{DS} = 30V, V _{GS} = 0V | - | - | 1 | μA |
| Gate to Source Leakage Current | I _{GSS} | V _{GS} = ±20V, V _{DS} = 0V | - | - | ±100 | nA |
| Gate Threshold Voltage | V _{GS(th)} | V _{DS} =V _{GS} , I _{Ds} =250μA | 1.0 | 1.5 | 2.5 | V |
| Static Drain to Source On-State Resistance | R _{DS(on)} | I _D = 25A, V _{GS} = 10V | - | 7.3 | 9.0 | mΩ |
| | | I _D = 15A, V _{GS} = 4.5V | - | 10.5 | 15 | mΩ |
| Input Capacitance | C _{iss} | V _{GS} =0V, V _{DS} =15V, Frequency=1.0MHz | - | 1162 | - | pF |
| Output Capacitance | C _{oss} | | - | 136 | - | pF |
| Reverse Transfer Capacitance | C _{rss} | | - | 101 | - | pF |
| Turn-ON Delay Time | t _{d(on)} | V _{DD} = 15V, I _{DS} = 30A, V _{GS} = 10V, R _G = 3Ω | - | 8 | - | ns |
| Rise Time | t _r | | - | 100 | - | ns |
| Turn-OFF Delay Time | t _{d(off)} | | - | 23 | - | ns |
| Fall Time | t _f | | - | 108 | - | ns |
| Total Gate Charge | Q _g | V _{DS} = 15V, V _{GS} = 10V, I _{DS} = 15A | - | 24 | - | nC |
| | Q _{gs} | | - | 4 | - | nC |
| | Q _{gd} | | - | 6 | - | nC |
| Diode Forward Voltage | V _{FSD} | I _S = 25A, V _{GS} = 0 | - | - | 1.2 | V |

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

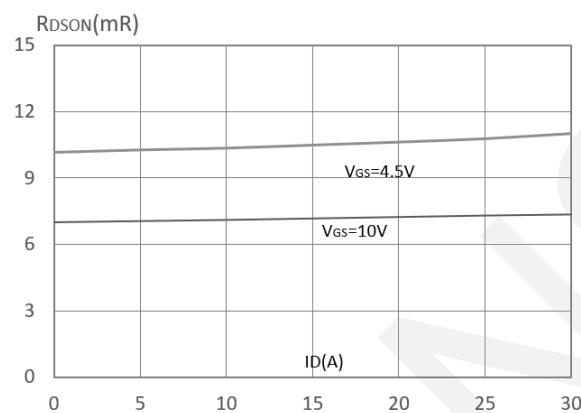
7.Typical electrical and thermal characteristics



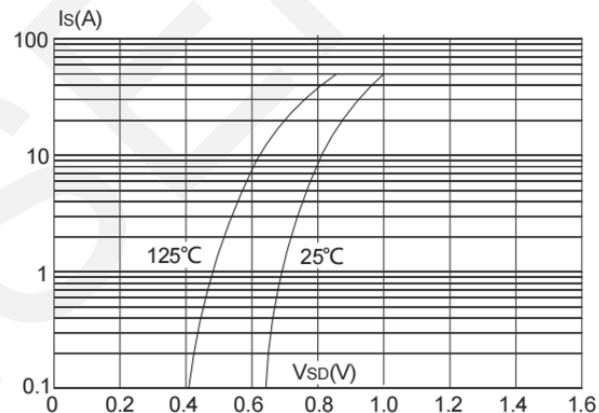
Output Characteristics



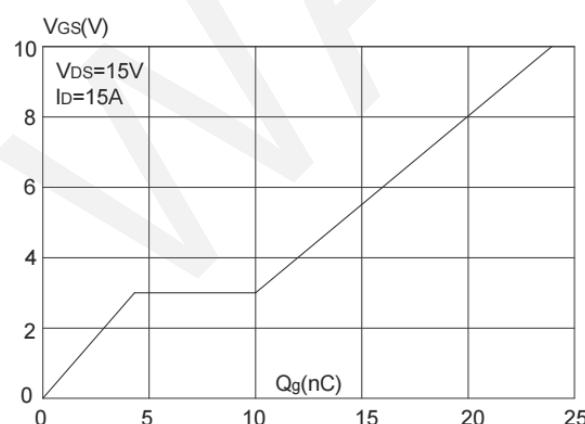
Typical Transfer Characteristics



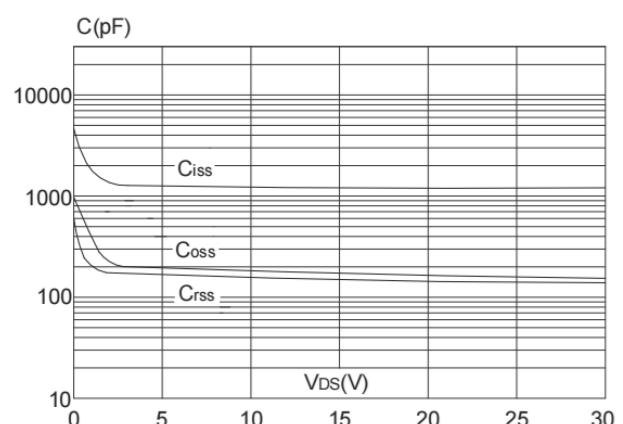
On-resistance vs. Drain Current



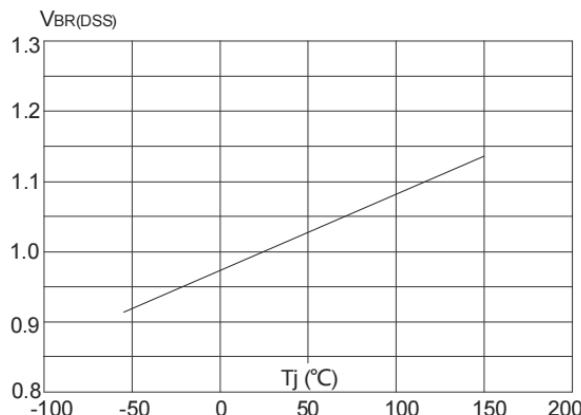
Body Diode Characteristics



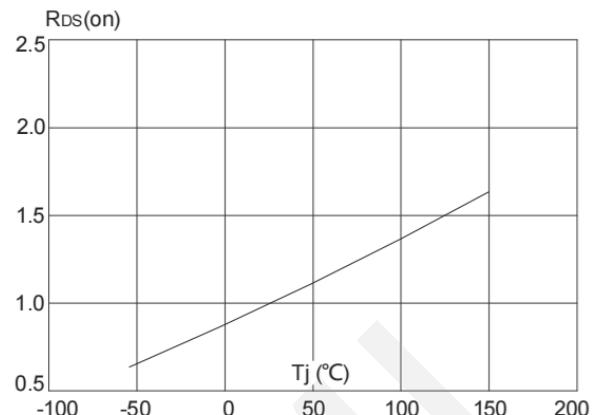
Gate Charge Characteristics



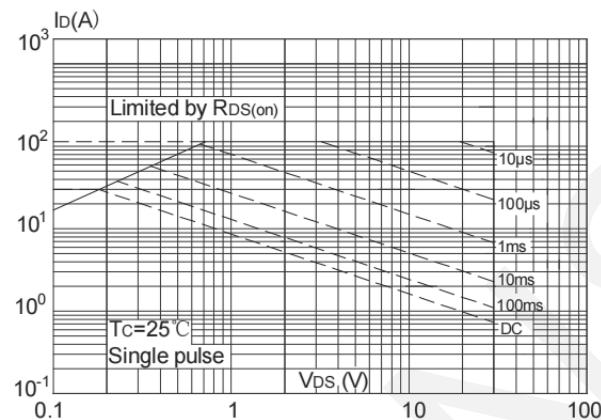
Capacitance Characteristics



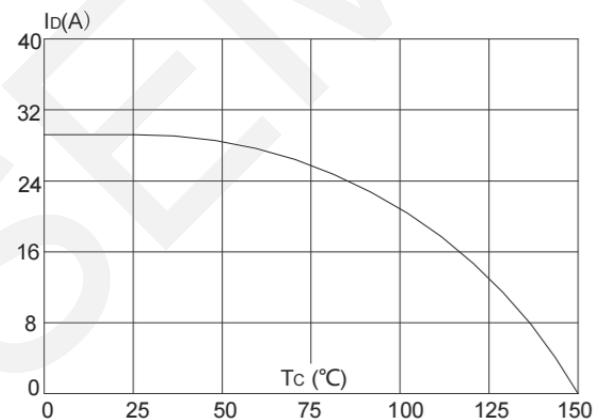
Normalized Breakdown Voltage vs.
Junction Temperature



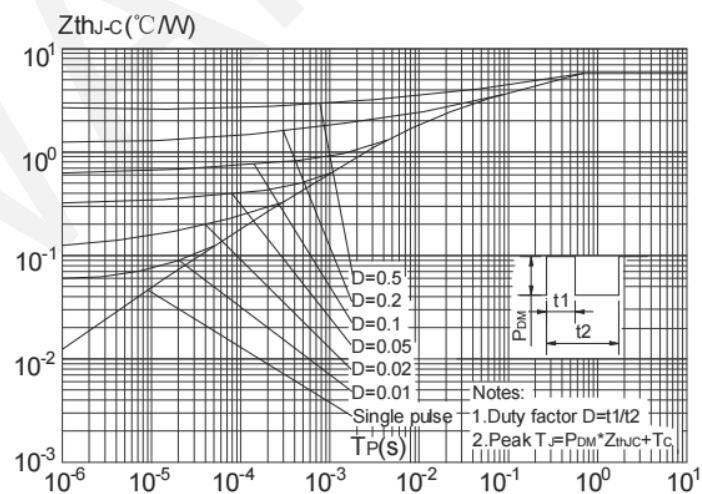
Normalized on Resistance vs.
Junction Temperature



Maximum Safe Operating Area



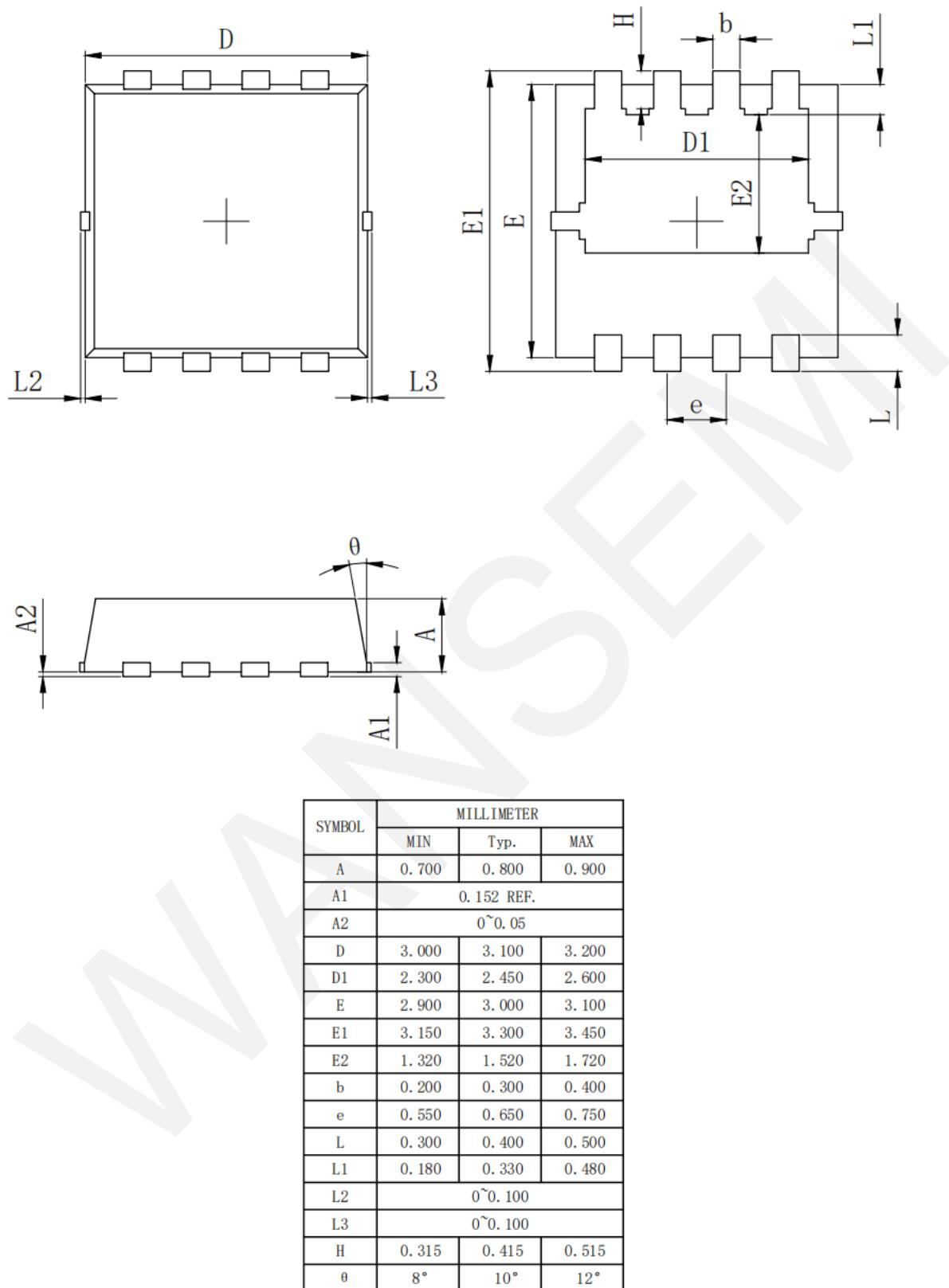
Maximum Continuous Drain Current vs.
Case Temperature



Maximum Effective Transient Thermal
Impedance, Junction-to-Case



8. Package Dimensions



9. Important Notice

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